Nanostructure characterization using aberration corrected STEM

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Aberration-corrected scanning transmission electron microscopy (STEM) is a very powerful method to directly characterize atomic-scale structures of surfaces and interfaces in many advanced materials.

In this talk, I will review our recent works on metal nanoparticle catalysts, surface structure characterization of titanium oxide, new STEM imaging mode for light element imaging, novel detector development and so on.